

### 1. General Description

The ASMN065D070N1 is a 650V, 70 mΩ Gallium Nitride (GaN) FET in an 8 x 8 DFN package. It is a normally-off device that combines asiasemitech latest high-voltage GaN HEMT with a low voltage silicon MOSFET to offer superior reliability and performance.

### 2. Features and Benefits

- JEDEC-qualified GaN technology
- Dynamic  $R_{DS(on)eff}$  production tested
- Wide gate safety margin
- Capable of reverse conduction
- Low gate charge
- RoHS compliant and Halogen-free packaging
- Achieves increased efficiency in both hard- and soft- switched circuits
  - Increased power density
  - Reduced system size and weight
  - Overall lower system cost
- Easy to drive with commonly-used gate drivers

### 3. Applications

- Fast charger
- Telecom power
- Data center
- Lighting

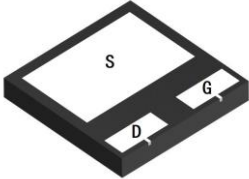
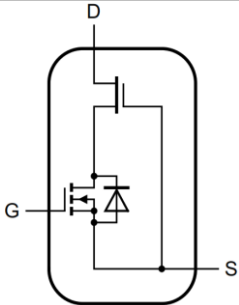
### 4. Key Specifications

Table 1. Key Specifications

Symbol	Parameter	Value	Unit
$V_{DS, max}$	Drain-source voltage	650	V
$I_{D, max}$	Continuous drain current @Tc = 25°C	24	A
$R_{DS(on), typ}$	Drain-source on-state resistance	70	mΩ
$Q_G, typ$	Total gate charge	9.5	nC
$Q_{RR, typ}$	Reverse recovery charge	110	nC

## 5. Pin Description

Table 2. Pin Description

Pin	Description	Bottom View	Graphic Symbol
G	Gate		
D	Drain		
S	Source		

## 6. Ordering Information

Table 3. Ordering Information

Part number	Package	Package Configuration	Marking Code
ASMN065D070N1	DFN 8*8	Source	ASMN065D070N1

## 7. Absolute Maximum Ratings

Table 4. Absolute Maximum Ratings (T<sub>c</sub>=25°C unless otherwise noted)

Parameter	Symbol	Min.	Max.	Unit.	Conditions
Drain to source voltage	V <sub>DSS</sub>	-	650	V	V <sub>GS</sub> = 0V
Transient drain to source voltage	V <sub>DSS(TR)</sub>	-	800		Non-repetitive Pulse for ≤10ms at 25°C
Gate to source voltage	V <sub>GSS</sub>	-20	20		
Maximum power dissipation	P <sub>D</sub>	-	96	W	T <sub>C</sub> = 25°C, <a href="#">Fig.1</a>
Continuous drain current	I <sub>D</sub>	-	24	A	T <sub>C</sub> = 25°C
		-	15	A	T <sub>C</sub> = 100°C
Pulsed drain current	I <sub>DM</sub>	-	TBD	A	Pulsed, t <sub>p</sub> ≤ 200μs, T <sub>C</sub> = 25°C
Operating temperature	T <sub>J</sub>	-55	150	°C	
Storage temperature	T <sub>S</sub>	-55	150	°C	

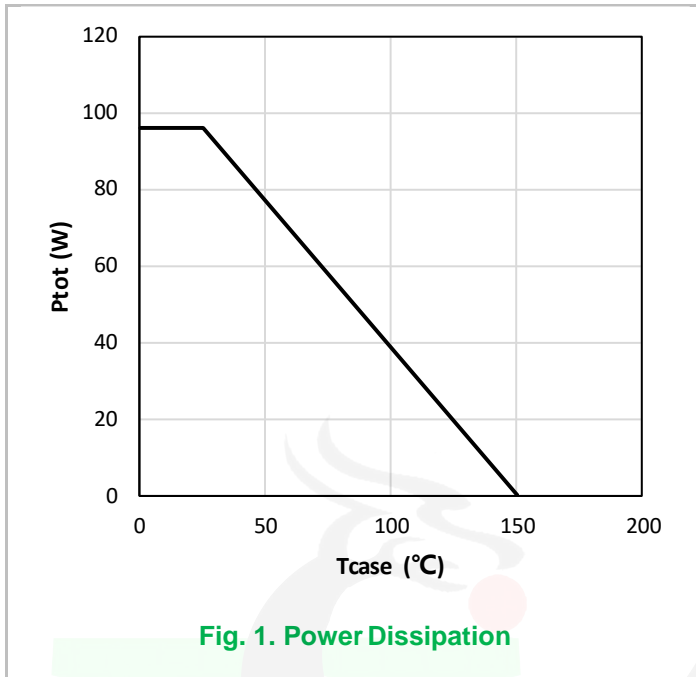


Fig. 1. Power Dissipation

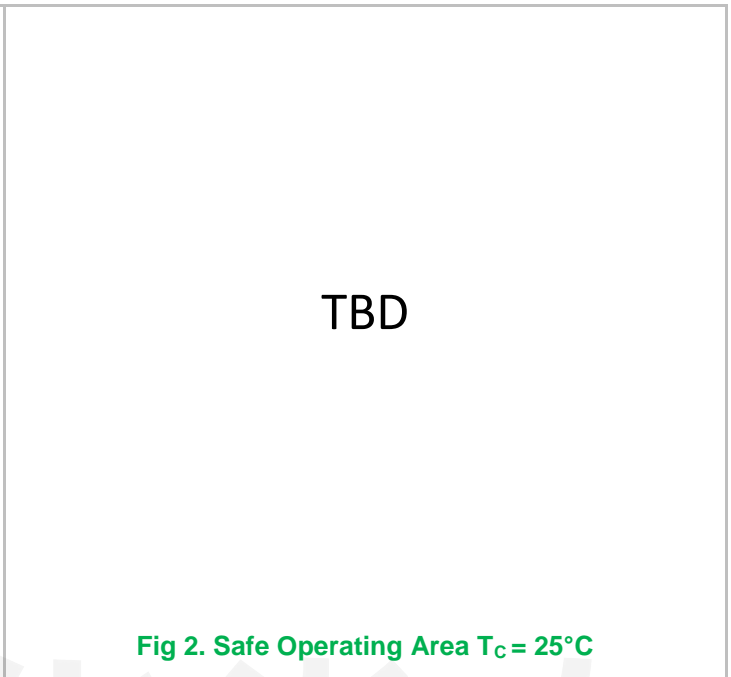


Fig 2. Safe Operating Area  $T_C = 25^\circ\text{C}$

## 8. Thermal Characteristics

Table 5. Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Thermal resistance (Junction-to-case)	$R_{th(j-c)}$	-	1.3	-	$^\circ\text{C}/\text{W}$	
Thermal resistance (Junction-to-ambient) <sup>a</sup>	$R_{th(j-a)}$	-	62	-	$^\circ\text{C}/\text{W}$	
Reflow soldering temperature	$T_{SOLD}$	-	-	260	$^\circ\text{C}$	reflow MSL3

Notes:

- Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm<sup>2</sup> copper area and 70μm thickness).

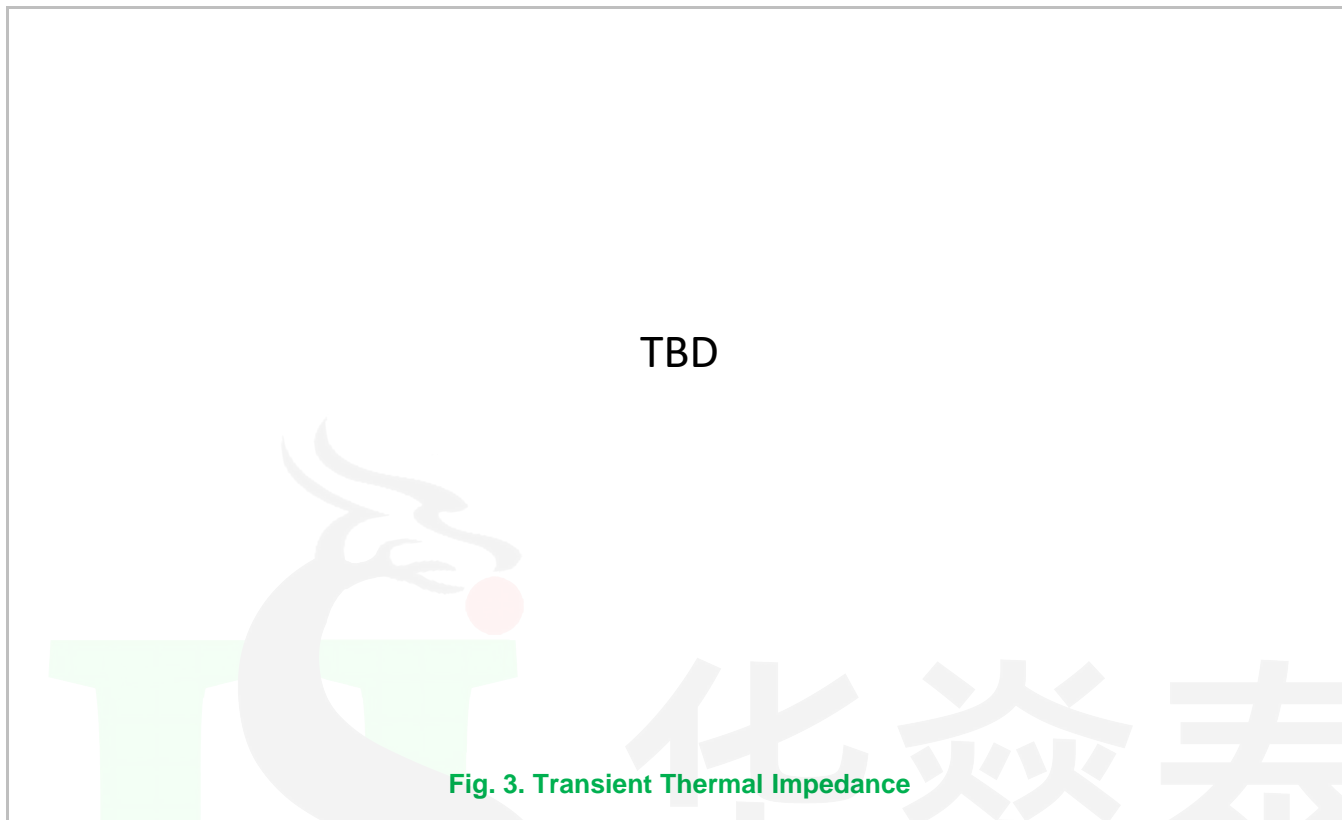


Fig. 3. Transient Thermal Impedance

## 9. Electrical Characteristics

Table 6. Electrical Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
<b>Forward Device Characteristics</b>						
Gate threshold voltage	$V_{GS(th)}$	-	4	-	V	$V_{DS} = V_{GS}$ , $I_D = 0.7mA$
Drain-source on-state resistance <sup>a</sup>	$R_{DS(on)}$	-	70	-	mΩ	$V_{GS} = 10V$ , $I_D = 16A$ , $T_J = 25^{\circ}C$ , Fig.18, Fig.19
		-	144	-		$V_{GS} = 10V$ , $I_D = 16A$ , $T_J = 150^{\circ}C$ , Fig.18, Fig.19
Drain-to-source leakage current	$I_{DSS}$	-	4	-	μA	$V_{DS} = 650V$ , $V_{GS} = 0V$ , $T_J = 25^{\circ}C$
		-	10	-		$V_{DS} = 650V$ , $V_{GS} = 0V$ , $T_J = 150^{\circ}C$
Gate-to-source leakage current	$I_{GSS}$	-	-	100	nA	$V_{GS} = 20V$ , $V_{DS} = 0V$ , $T_J = 25^{\circ}C$
		-	-	-100		$V_{GS} = -20V$ , $V_{DS} = 0V$ , $T_J = 25^{\circ}C$

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Input capacitance	$C_{ISS}$	-	765	-	pF	$V_{GS} = 0V, V_{DS} = 400V, f = 1MHz, \text{Fig. 8}$
Output capacitance	$C_{OSS}$	-	60	-		
Reverse transfer capacitance	$C_{RSS}$	-	1.1	-		
Output capacitance, energy related <sup>a</sup>	$C_{O(er)}$	-	110	-	pF	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 400V, \text{Fig. 9}$
Output capacitance, time related <sup>b</sup>	$C_{O(tr)}$	-	225	-		
Total gate charge	$Q_G$	-	9.5	-	nC	$V_{DS} = 400V, V_{GS} = 0V \text{ to } 10V, I_D = 16A, \text{Fig. 11}$
Gate-source charge	$Q_{GS}$	-	4.2	-		
Gate-drain charge	$Q_{GD}$	-	2	-		
Output charge	$Q_{OSS}$	-	90	-	nC	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 400V$
Turn-on delay time	$t_{D(on)}$	-	38	-	ns	$V_{DS} = 400V, V_{GS} = 0V \text{ to } 12V, I_D = 16A, R_{G_{on}} = 51\Omega, R_{G_{off}} = 2\Omega, \text{Fig. 14; Fig. 15}$
Rise time	$t_R$	-	17	-		
Turn-off delay time	$t_{D(off)}$	-	37	-		
Fall time	$t_F$	-	7	-		
<b>Reverse Device Characteristics</b>						
Reverse voltage <sup>c</sup>	$V_{SD}$	-	1.8	-	V	$V_{GS} = 0V, I_S = 16A, T_J = 25^\circ C, \text{Fig. 12}$
		-	1.3	-		$V_{GS} = 0V, I_S = 8A, T_J = 25^\circ C, \text{Fig. 12}$
Reverse recovery time	$t_{RR}$	-	24	-	ns	$I_S = 16A, V_{DD} = 400V, di/dt = 1000A/\mu s, \text{Fig. 16; Fig. 17}$
Reverse recovery charge	$Q_{RR}$	-	110	-	nC	$V_{GS} = 0V, I_S = 16A, T_J = 25^\circ C, \text{Fig. 16; Fig. 17}$

Notes:

- Equivalent capacitance to give same stored energy from 0V to 400V
- Equivalent capacitance to give same charging time from 0V to 400V
- Includes dynamic  $R_{DS(on)}$  effect

9.1 Electrical characteristics(curves) ( $T_C=25^\circ\text{C}$  unless otherwise stated)

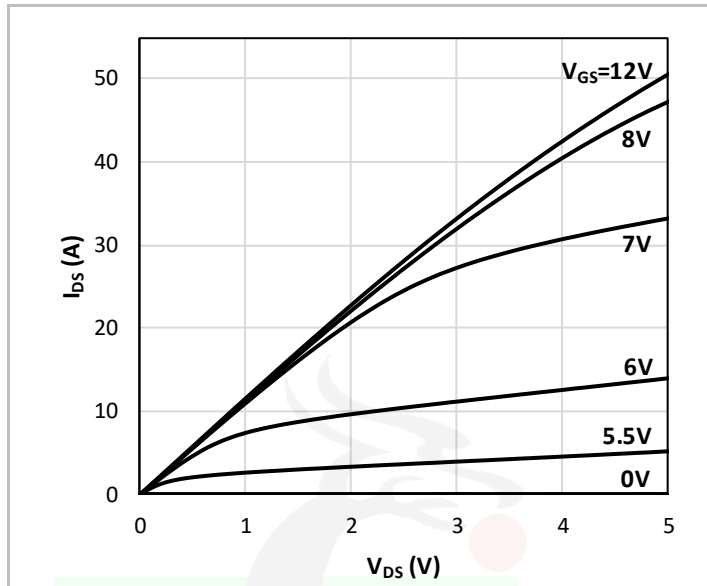


Figure 4. Typical Output Characteristics  
 $T_J = 25^\circ\text{C}$

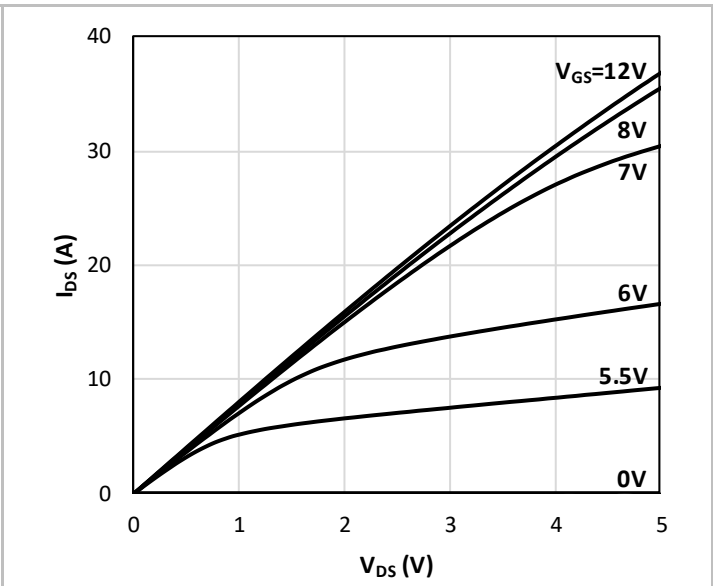


Figure 5. Typical Output Characteristics  
 $T_J = 150^\circ\text{C}$

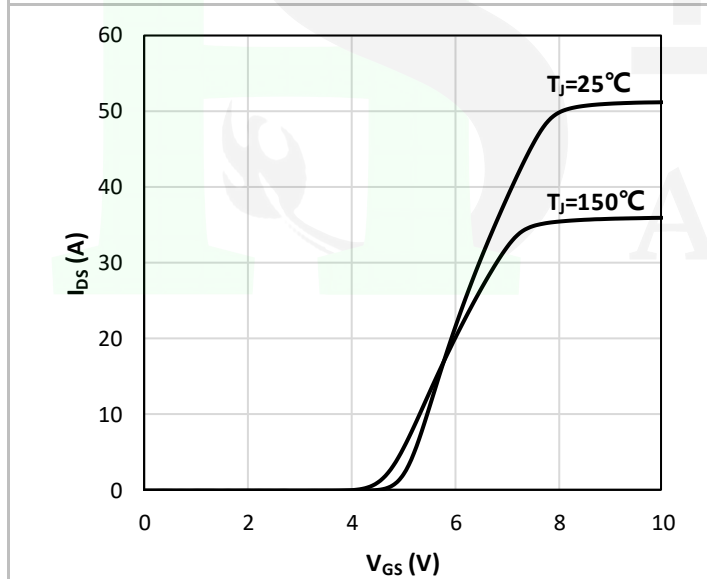


Fig. 6. Typical Transfer Characteristics  
 $V_{DS} = 5\text{V}$

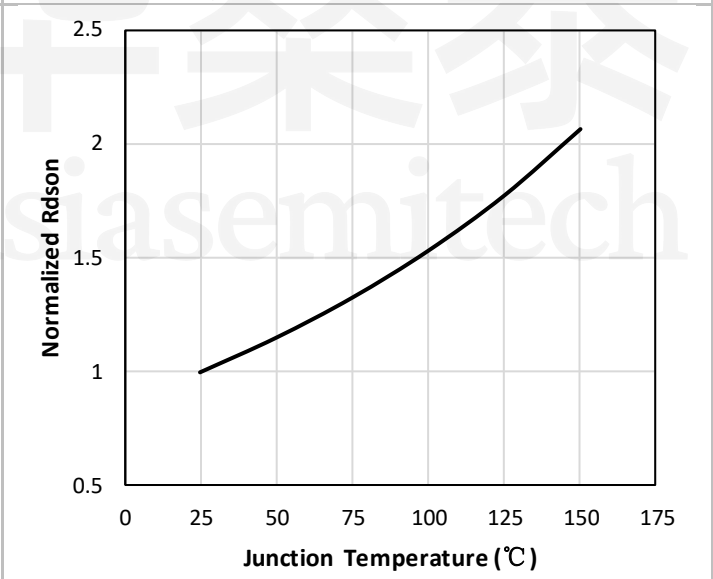


Fig. 7. Normalized On-resistance  
 $I_D = 16\text{A}, V_{GS} = 10\text{V}$

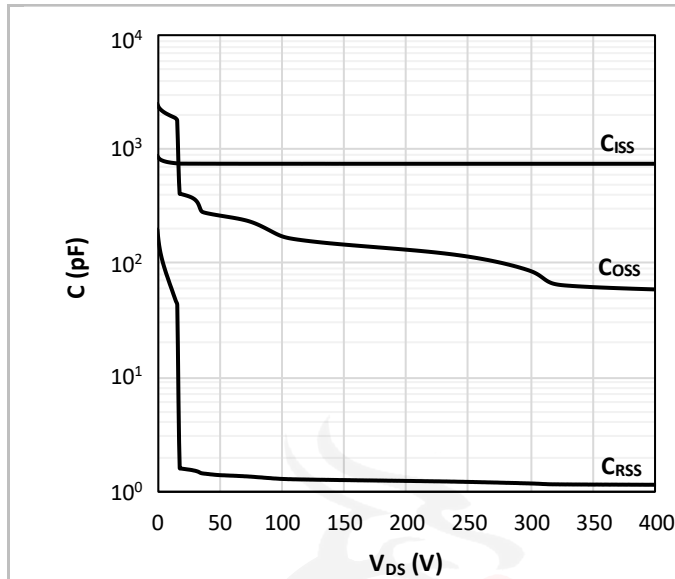


Fig. 8. Typical Capacitance

V<sub>GS</sub> = 0V, f = 1MHz

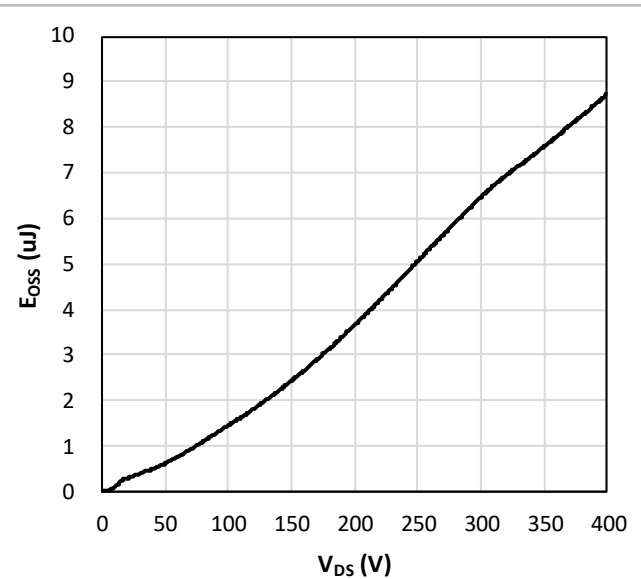


Fig. 9. Typical Coss Stored Energy

V<sub>GS</sub> = 0V, f = 1MHz

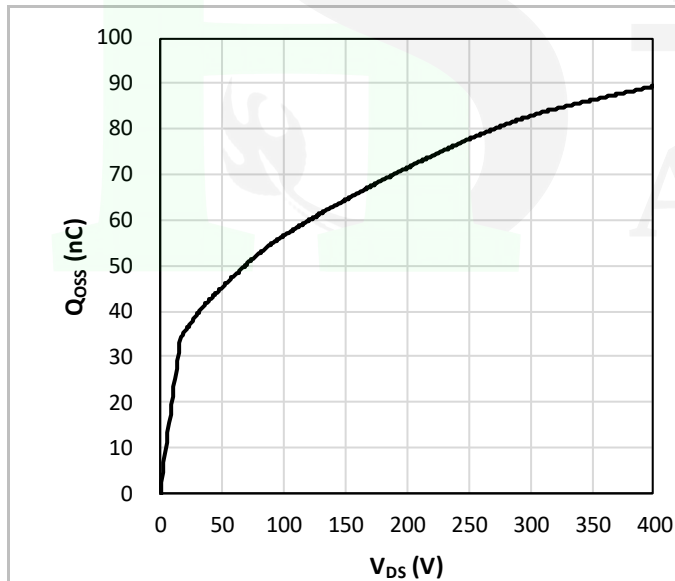


Fig. 10. Typical Q<sub>oss</sub>

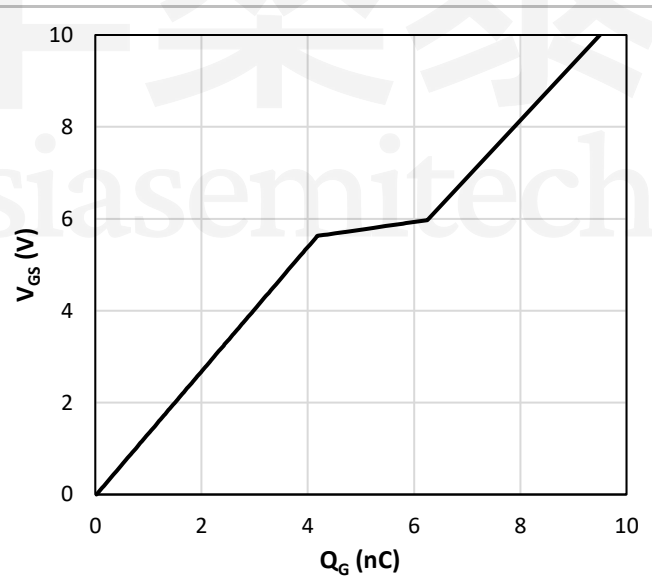


Fig. 11. Typical Gate Charge

I<sub>DS</sub> = 16A, V<sub>DS</sub> = 400V

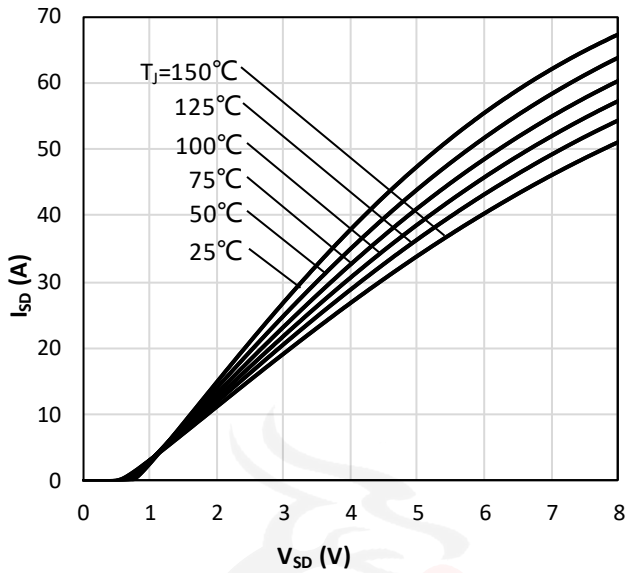


Fig. 12. Forward Characteristics of Rev. Diode

$$I_{SD} = f(V_{SD})$$

TBD

Fig. 13. Typical  $R_{DS(on)}$

## 10. Test Circuits

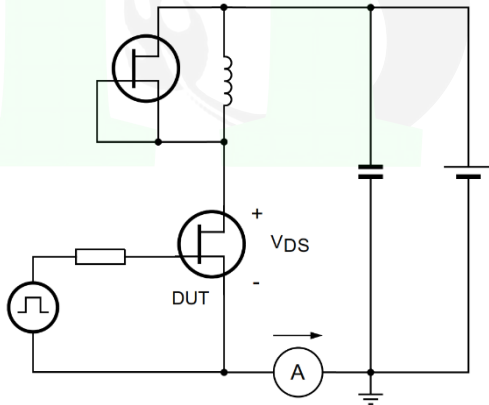


Fig. 14. Switching Time Test Circuit

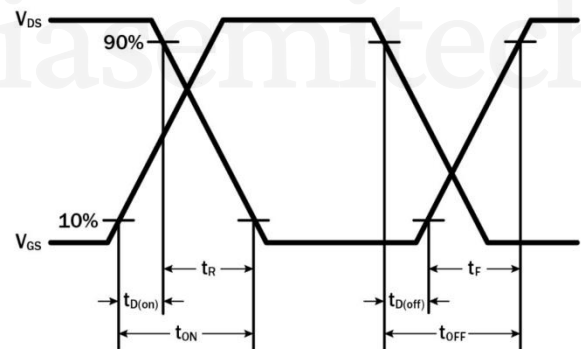
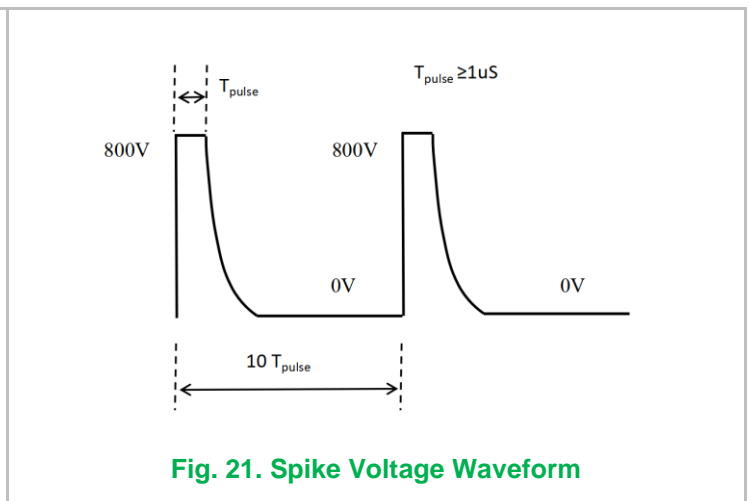
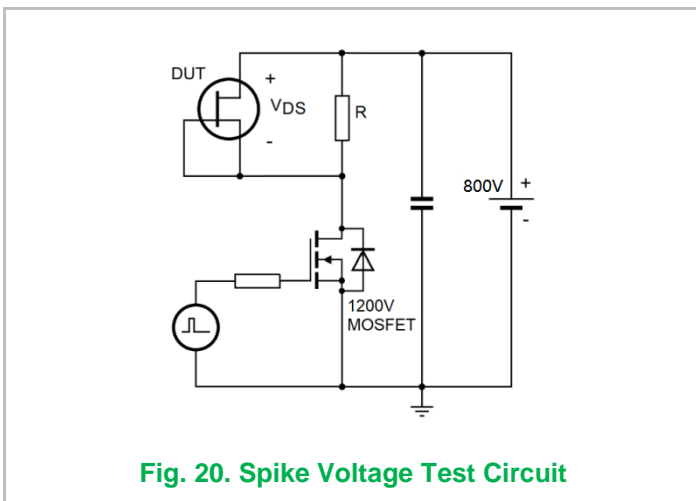
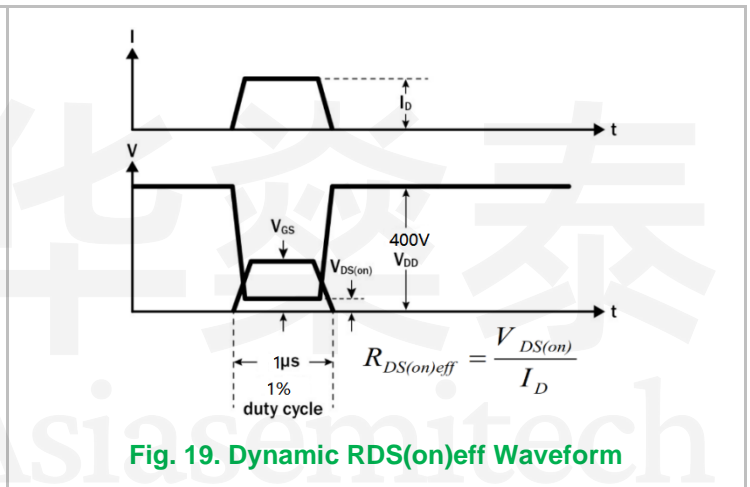
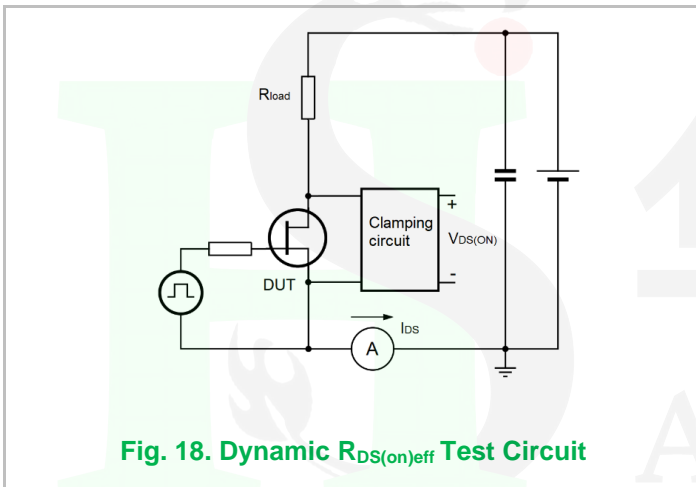
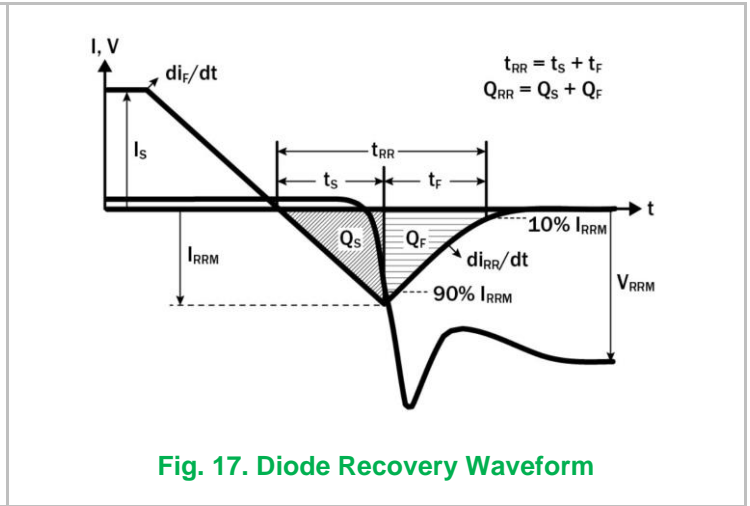
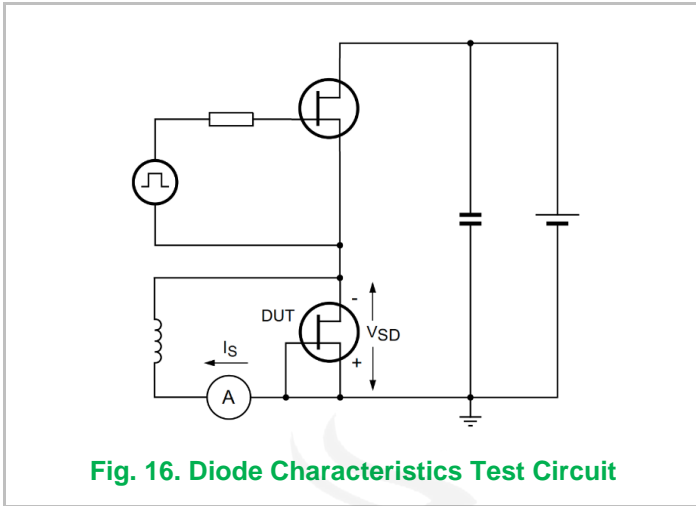


Fig. 15. Switching Time Waveform



## 11. Package Information

### 11.1 DFN 8x8 Package Information

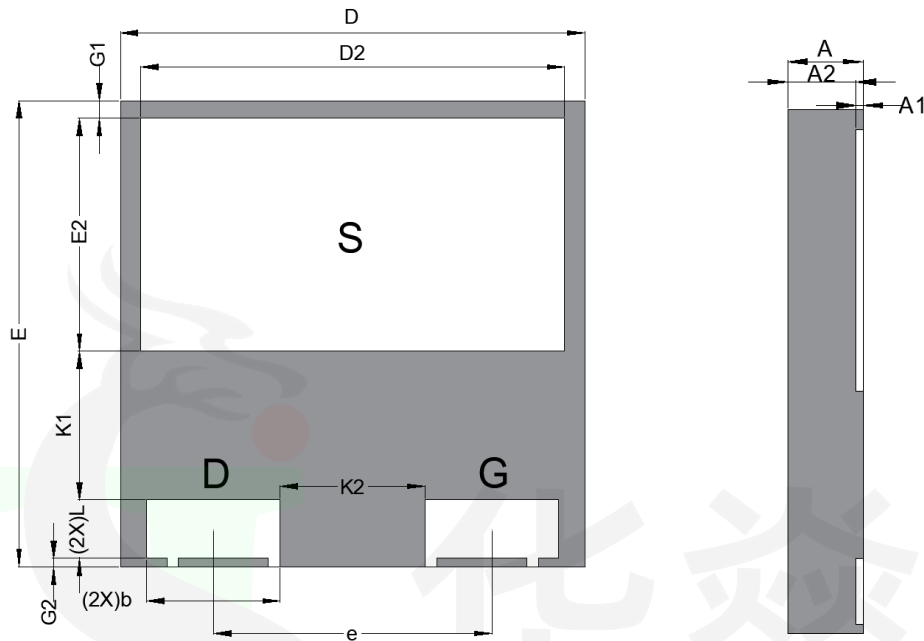


Fig. 22. DFN 8x8 Package Outline

DIM	mm			in		
	MIN	NOM	MAX	MIN	NOM	MAX
A	1.35	1.40	1.45	0.053	0.055	0.057
A1	0.007	0.012	0.017	/		
A2	1.343	1.388	1.433	/		
b	2.25	2.30	2.35	0.088	0.090	0.092
D	7.90	8.00	8.10	0.308	0.312	0.316
D2	7.25	7.30	7.35	0.283	0.285	0.287
E	7.90	8.00	8.10	0.308	0.312	0.316
E2	4.20	4.25	4.30	0.164	0.166	0.168
e	4.8BSC			0.187BSC		
K1	2.50	-	-	0.098	-	-
K2	2.50	-	-	0.098	-	-
L	0.75	0.80	0.85	0.029	0.031	0.033
G1	0.25	0.30	0.35	0.010	0.012	0.014
G2	0.10	0.15	0.20	0.004	0.006	0.008

## 12. Important Notice

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